

PATENT ABSTRACTS OF JAPAN

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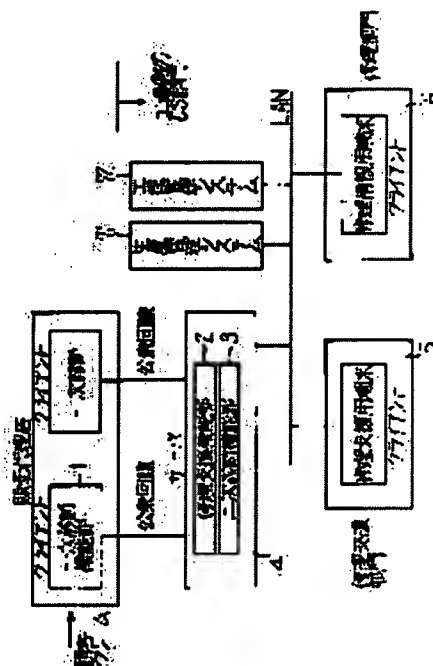
(54) CLAIM DEALING SUPPORTING METHOD

(57)Abstract:

PURPOSE: To maintain and improve the satisfaction of customers in the claim dealing supporting method to be used for processing the claims of customers on mass-produced electronic equipment.

CONSTITUTION: This method is provided with a first knowledge base relating the state of any fault with the correspondence of fault factor and countermeasure by using the knowledge of a designer, an inference part (first-order diagnostic function part 1) for inferring the fault and countermeasure corresponding to the inputted fault state by using the first knowledge base, a repair supporting part 5, a second knowledge base relating the correspondence of a test item and a testing

method, the correspondence of that test item, tested result and next test item and the correspondence of the fault state in the past, its factor and testing method by using the knowledge of the designer, and a retrieval/inference part (second-order diagnostic function part 3) for inferring the fault factor by retrieving the second knowledge base. The retrieval/ inference part is constituted so that similar fault states and factor candidates in the past are extracted from the fault state transmitted by the inference part, any factor is inferred by performing tests according to the correspondent procedure of tests and the inference is repeated



until the coincidence of the inferred factor and the factor candidate is confirmed.

LEGAL STATUS

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